



PATENT APPLICATION
PO-8734
BTS054034

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICATION OF)
MARKUS HAIML ET AL)
SERIAL NUMBER: 10/565,909)
DATE SUBMITTED: JANUARY 25, 2006)
TITLE: ANALYTICAL SYSTEM, AND)
METHOD FOR ANALYZING)
NONLINEAR OPTICAL SIGNALS)

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. 1.97(b)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This disclosure statement under 37 CFR 1.97 & 1.98 is submitted before the first Office Action in order that the Patent and Trademark Office may consider the relevancy of certain information to the invention described and claimed in the subject application, and in compliance with the regulations concerning information disclosure statements. Copies of the foreign documents and articles listed on the attached Form PTO-1449 are enclosed.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an enveloped addressed to: Commissioner for Patents, Alexandria, VA 22313-1450 on 9/20/06

Date

Aron Preis, Reg. No. 29,426
Name of applicant, assignee or Registered Representative


Signature
September 20, 2006

Date

Concise statements of the presently understood relevance of each of the documents are found in the specification filed.

This Information Disclosure Statement should not be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, that any document mentioned herein constitutes prior art, or that the documents listed severally or in any combination with one another or with any other information, are believed to render any claim in the subject application *prima facie* unpatentable.

Respectfully submitted,

By _____


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Form PTO 1449 Rev. 7-80	U.S. Department of Commerce Patent and Trademark Office LIST OF PRIOR ART CITED BY APPLICANT (Use Several Sheets If Necessary)	Atty. Docket No. PO8734/BTS054034	Serial No. 10/565,909
SEP 22 2006	Applicant Markus Haiml et al	Filing Date January 25, 2006	Group No.

U.S. PATENT DOCUMENTS

EXAMINER INITIAL TRADEMAKERS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA	**4,245,800	01/20/81	Henderson	244	3.13	
AB	**5,034,613	07/23/91	Denk et al	250	458.1	
AC	5,445,934	08/29/95	Fodor et al	435	6	
AD	**5,459,574	10/17/95	Lee et al	356	437	
AE	5,742,355	04/21/98	(Bel. to corresp. to WO De Haan et al 96/15625) 348	607		
AF	5,822,472	10/13/98	(Bel. to corresp. to WO Danielzik et al 95/33198) 385	12		
AG	5,959,292	09/28/99	(Bel. to corresp. to WO Duvaneck et al 95/33198) 250	227.11		
AH	6,078,705	06/20/00	(Bel. to corresp. to WO Neuschäfer et al 96/35940) 385	12		
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AJ	6,198,869 B1	03/06/01	(Bel. to corresp. to WO Kraus et al 98/22799) 385	129		
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No*
AL		95/33197 A1	12/07/95	World				
AM		01/13096 A1	02/22/01	World				X
AN		02/46756 A1	06/13/02	World				X
AO		**00/71028	11/30/00	World				
AP		**02/054071	07/11/02	World				

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AR	Science, 248, April 6, 1990, pages 73-76, Winfried Denk et al, "Two-Photon Laser Scanning Fluorescence Microscopy"
AS	Applied Physics, B, 73 (month unavailable) 1990, pages 869-871, G.L. Duvaneck et al, "Evanescence-field-induced two-photon fluorescence: excitation of macroscopic areas of planar waveguides"
AT	Analytica Chimica Acta, 469, (month unavailable) 2002, pages 49-61, Gert L. Duvaneck et al, "Planar waveguides for ultra-high sensitivity of the analysis of nucleic acids"

EXAMINER	DATE CONSIDERED
EXAMINER Initial if references considered, whether or not citation is in conformance with MPEP 609: Draw line through if not in conformance and not considered. Include copy of this form with next communication to applicant.	

* Neither English Language Equivalent nor an English Language Translation is available.

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	AA	6,384,912 B2	05/07/02	(Bel. to corresp. to WO Kraus et al	98/22799) 356	246	
	AB	6,437,345 B1	08/20/02	(Bel. to corresp. to WO Bruno-Raimondi et al	99/58963) 250	458.1	
	AC	6,510,263 B1	01/21/03	(Bel. to corresp. to WO Maisenholder et al	01/55691) 385	37	
	AD	6,873,764 B2	03/29/05	(Bel. to corresp. to WO Maisenhoelder et al	01/55691) 385	37	
	AE	6,961,490 B2	11/01/05	(Bel. to corresp. to WO Maisenholder et al	01/55691) 385	37	
	AF	7,060,957 B2	06/13/06	(Bel. to corresp. to WO Lange et al	01/84182) 250	208.1	
	AG	2001/0001021 A1	05/10/01	(Bel. to corresp. to WO Kraus et al	98/22799) 385	12	
	AH	2002/0076154 A1	06/20/02	(Bel. to corresp. to WO Maisenhoelder et al	01/55691) 385	37	
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							Yes	No*
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	AR	Peregrinus, 232, (month unavailable) 1983, pages 1-30, M.L. Meade, "Lock in amplifiers: principles In applications"
	AS	IEEE Journal of Quantum Electronics, Vol. 31, No. 9, September 1995, pages 1705-1708, T. Spirig et al, "The Lock-In CCD-Tow-Dimensional Synchronous Detection of Light"
	AT	IEEE Transactions of Electron Devices, Vol. 44, No. 10, October 1997, pages 1643-1647, Thomas Spirig et al, "The Multitap Lock-In CCD with Offset Subtraction"
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	AA	2003/0148542 A1	08/07/03	(Bel. to corresp. to WO Pawlak et al	01/92870) 436	518	
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	AG						
	AH						
	AI						
	AJ						
	AK						

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	AN							
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	AP							

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	AR	J. Opt. Soc. Am. A, Vol. 18, No. 8, August 2001, pages 1972-1979, Arnaud Dubois, "Phase-map measurements by interferometry with sinusoidal phase modulation and four integrating buckets"
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